



Course guide

240EM032 - 240EM032 - Advanced Characterization of Materials

Last modified: 27/05/2024

Unit in charge: Barcelona East School of Engineering

Teaching unit: 702 - CEM - Department of Materials Science and Engineering.

Degree: ERASMUS MUNDUS MASTER'S DEGREE IN ADVANCED MATERIALS SCIENCE AND ENGINEERING (Syllabus 2014). (Optional subject).

Academic year: 2024

ECTS Credits: 4.5

Languages: Spanish

LECTURER

Coordinating lecturer: JOSE M. MANERO PLANELLA

Others: Primer quadrimestre:
JONATHAN CAILLOUX - T10
JOSE M. MANERO PLANELLA - T10
MARTA PEGUEROLES NEYRA - T10
JOAN JOSEP ROA ROVIRA - T10

PRIOR SKILLS

Knowledge of engineering materials, physics and chemistry

REQUIREMENTS

DEGREE COMPETENCES TO WHICH THE SUBJECT CONTRIBUTES

Specific:

CEMCEM-04. (ENG) Realitzar estudis de caracterització, avaluació i certificació de materials segons les seves aplicacions

Transversal:

06 URI N3. EFFECTIVE USE OF INFORMATION RESOURCES - Level 3. Planning and using the information necessary for an academic assignment (a final thesis, for example) based on a critical appraisal of the information resources used.

TEACHING METHODOLOGY

The classes will be taught in theoretical format, problems where the specific competences of the subject will be introduced. Face-to-face activities will be carried out to work on oral and written communication and teamwork.

LEARNING OBJECTIVES OF THE SUBJECT

The objective of the subject is that the student acquires knowledge of the different existing experimental techniques for the microstructural and physicochemical characterization of materials. Depending on the problem or needs of each case, the student must have sufficient criteria to select the most appropriate technique, as well as the interpretation of their results.



STUDY LOAD

Type	Hours	Percentage
Hours small group	13,5	12.00
Self study	72,0	64.00
Hours large group	27,0	24.00

Total learning time: 112.5 h

CONTENTS

1. Introduction. The concept of microstructure.title english

Description:

Structure-property relationships. Microstructural scale. Microstructural parameters. Interatomic bonding in solids. Crystalline and Amorphous phases. The crystal lattice.

Specific objectives:

Related activities:

Full-or-part-time: 4h

Theory classes: 4h

2. X-ray diffraction analysis of the crystalline structure

Description:

Scattering of radiation by crystals. Reciprocal Space. X-Ray diffraction methods. The X-Ray diffractometer. Powder diffraction technique. Diffraction analysis.

Full-or-part-time: 3h

Theory classes: 3h

3. Contact angle in surface analysis

Description:

Determining surface energy of a homogeneous solid surface. Equation of state. Measuring contact angle. Static and dynamic sessile drop. Captive air bubble method.

Specific objectives:

Related activities:

Full-or-part-time: 5h

Theory classes: 5h

4. Characterization of surface roughness and porosimetry.

Description:

Roughness evaluation. Techniques for roughness evaluation: perfilometry, AFM. What is porosity? Basic principles of the porosity techniques.

Specific objectives:

Related activities:

Full-or-part-time: 4h

Theory classes: 4h

5. Spectroscopic analysis of surface composition.

Description:

X-Ray Photoelectron Spectroscopy. Fourier transform infrared spectroscopy.

Specific objectives:

Related activities:

Full-or-part-time: 4h

Theory classes: 4h

ELECTRON MICROSCOPY OF MATERIALS: 6 Interaction of an electron beam with a specimen. The physics of the process.

Description:

Electron-sample interactions: Secondary electrons. Backscattered electrons. X-Ray Continuum. Characteristic X- Rays. Auger Electron Emission. Photon-specimen interactions: Absorption. Secondary fluorescence

Specific objectives:

Related activities:

Full-or-part-time: 4h

Theory classes: 4h

ELECTRON MICROSCOPY OF MATERIALS 7. Fundamentals and techniques.

Description:

Electron beams as waves. Lenses for electron beams. Lens defects and resolution. Structure of transmission electron microscopes. Mechanism of images formation; contrast. Structure of scanning electron microscopes (SEM, ESEM).

Specific objectives:

Related activities:

Full-or-part-time: 4h

Theory classes: 4h



ELECTRON MICROSCOPY OF MATERIALS:8. Sample preparation.

Description:

Sample preparation for SEM. Sample preparation for TEM: Jet-polishing methods. Ion beam milling technique. Focus ion beam (FIB). Ultramicrotome cutting. Replica technique for surfaces. Extraction replica. Preparation of Powders.

Specific objectives:

Related activities:

Full-or-part-time: 5h
Theory classes: 5h

ELECTRON MICROSCOPY OF MATERIALS: 9. Electron diffraction

Description:

Fundamentals. Debye-Scherrer patterns, standardization. Reciprocal lattice. Electron diffraction patterns. Method of Rn ratios. Correlation of image and diffraction pattern (magnetic rotation). Kikuchi lines. Examples of indexing single-crystals diffraction patterns.

Specific objectives:

Related activities:

Practical exercises for the electron diffraction patterns

Full-or-part-time: 5h 30m
Theory classes: 5h 30m

ELECTRON MICROSCOPY OF MATERIALS: 10. Contrast theory and applications

Description:

Dynamical theory. Application of the basic equation to real crystals: derivation of the contrast of a dislocation. The g.b criterion. Determination of Burger vector b. Determination of dislocation densities. Analysis of twin structures.

Specific objectives:

Related activities:

Full-or-part-time: 3h
Theory classes: 3h

GRADING SYSTEM

The student's grade will be: Final grade = 0.5 (1st partial exam) + 0.5 (2nd partial exam). In case of re-evaluation, the student's grade will be: Final grade = Reevaluation exam.

The students will be able to access the re-assessment test that meets the requirements set by the EEBE in its Assessment and Permanence Regulations (<https://eebe.upc.edu/ca/estudis/normatives-academiques/documents/eebe-normativa-avaluacio-i-permanencia-18-19-aprovat-je-2018-06-13.pdf>)

EXAMINATION RULES.



BIBLIOGRAPHY

Basic:

- Zhang, Sam; Li, Lin; Kumar, Ashok. Materials characterization techniques [on line]. CRC Press, 2008 [Consultation: 09/10/2018]. Available on: <https://ebookcentral.proquest.com/lib/upcatalunya-ebooks/detail.action?docID=1446735>. ISBN 9781420042955.
- Advanced techniques for materials characterization [on line]. Trans Tech Pubn, 2009 [Consultation: 09/10/2018]. Available on: <https://ebookcentral.proquest.com/lib/upcatalunya-ebooks/detail.action?docID=1869163>. ISBN 0878493794.
- Leng, Yang. Materials characterization : introduction to microscopic and spectroscopic methods [on line]. 2nd ed. Weinheim, Germany: John Wiley & Sons, cop. 2013 [Consultation: 19/05/2020]. Available on: <https://onlinelibrary.wiley.com/doi/book/10.1002/9783527670772>. ISBN 9783527670772.
- Sibilía, John P. A Guide to materials characterization and chemical analysis. New York, NY [etc.]: VCH, cop. 1988. ISBN 0895732696.
- Cullity, B. D.; Stock, S. R. Elements of X-ray diffraction. 3rd ed. Upper Saddle River, NJ: Prentice-Hall, cop. 2014. ISBN 9781292040547.
- Beeston, B. E. Electron diffraction and optical diffraction techniques. Amsterdam [etc.]: North-Holland, 1972. ISBN 0720442532.
- Heimendahl, Manfred von. Electron microscopy of materials : an introduction. New York: Academic Press, 1980. ISBN 0127251502.